Docket No. 2001-1300/24061.413 Customer No. 42717

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant:

Kuan-Lun Chang, et al.

Docket No.:

2001-1300 / 24061.413

Serial No.:

10/772,940

Examiner:

Quoc Dinh Hoang

Filed:

February 5, 2004

Art Unit:

2818

For:

Method of Forming a Shallow

Conf. No.:

6082

Trench-Deep Trench Isolation Region for a BiCMOS/CMOS

Technology

RESPONSE TO RESTRICTION REQUIREMENT

Commissioner for Patents Mail Stop: Amendment

PO Box 1450

Alexandria, VA 22313-1450

Dear Sir:

The present paper is being submitted in response to the Restriction Requirement Office Action dated August 9, 2005 in the above-identified application.

Election of Claims begins on page 2 of this paper.

Amendments to the Claims are reflected in the Listing of Claims which begins on page 3 of this paper.

Remarks begin on page 11 of this paper.

## I. Election

In the Office Action mailed August 9, 2005, the Examiner alleges that the application contains claims directed to two inventions and, thus, required restriction of either:

Group I: Claims 29-35, drawn to a shallow trench-deep trench structure in a semiconductor substrate; or

Group II: Claims 1-28, drawn to a process of making an isolation region in semiconductor substrate.

In response, Applicants hereby elect Group II, corresponding to claims 1-28. Applicants' election is made with traverse on the grounds that the embodiments delineated by the Examiner are not patentably distinct and therefore constitute a single invention concept.